# MR2A08AM

**512K x 8 MRAM Memory**

## FEATURES

- + 3.3 Volt power supply
- Fast 35ns read/write cycle
- SRAM compatible timing
- Unlimited read & write endurance
- Data always non-volatile for >20-years at temperature
- RoHS-compliant TSOPII package
- AEC-Q100 Grade 1 Automotive Temperature (-40 to +125 °C)


## BENEFITS

- One memory replaces FLASH, SRAM, EEPROM and BBSRAM in system for simpler, more efficient designs
- Improves reliability by replacing battery-backed SRAM
- Automatic data protection on power loss

RoHS

## INTRODUCTION

The **MR2A08AM** is a 4,194,304-bit magnetoresistive random access memory (MRAM) device organized as 524,288 words of 8 bits. The MR2A08AM offers SRAM compatible 35ns read/write timing with unlimited endurance. Data is always non-volatile for greater than 20-years. Data is automatically protected on power loss by low-voltage inhibit circuitry to prevent writes with voltage out of specification. The MR2A08AM is the ideal memory solution for applications that must permanently store and retrieve critical data and programs quickly.

The **MR2A08AM** is available in a small footprint 400-mil, 44-lead plastic small-outline TSOP type-II package which is compatible with similar low-power SRAM products and other non-volatile RAM products.

The **MR2A08AM** provides highly reliable data storage over a wide range of temperatures. The product is offered in AEC-Q100 grade 1 automotive temperature (-40 to +125 °C) range options.

## CONTENTS

## 1. DEVICE PIN ASSIGNMENT

**Figure 1.1 Block Diagram**

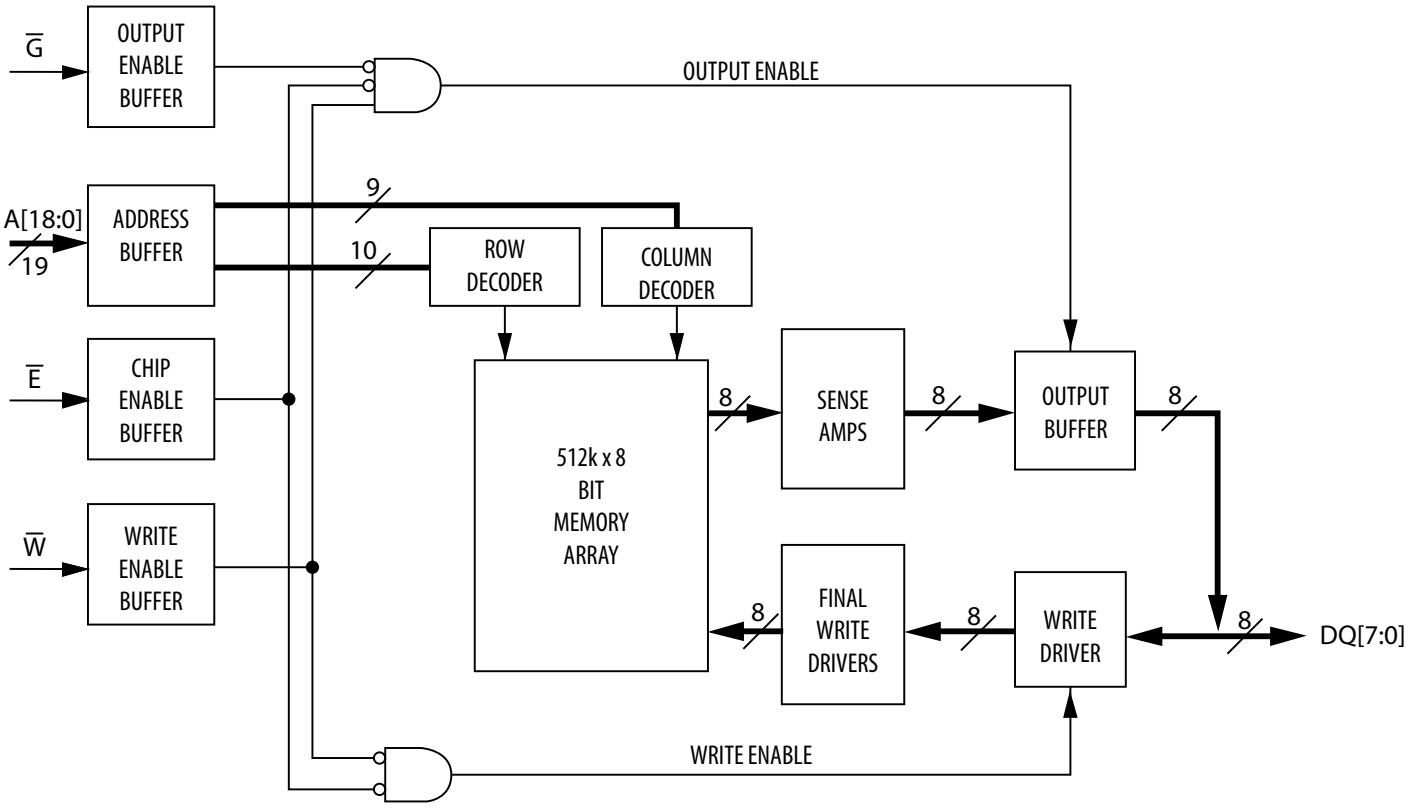
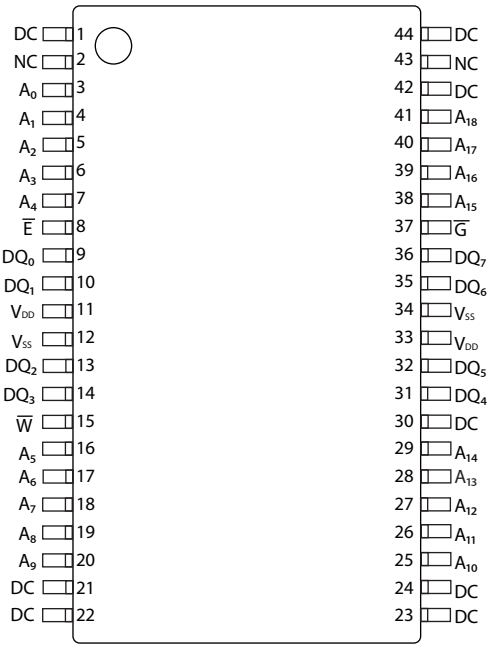



**Table 1.1 Pin Functions**

| Signal Name | Function |
|---|---|
| A | Address Input |
| $\overline{E}$ | Chip Enable |
| $\overline{W}$ | Write Enable |
| $\overline{G}$ | Output Enable |
| DQ | Data I/O |
| $V_{DD}$ | Power Supply |
| $V_{SS}$ | Ground |
| DC | Do Not Connect |
| NC | No Connection |

**Figure 1.2 Pin Diagrams for Available Packages (Top View)**




**44 Pin TSOP II**

**Table 1.2 Operating Modes**

| $\overline{E}$[1] | $\overline{G}$[1] | $\overline{W}$[1] | Mode | $V_{DD}$ Current | DQ[7:0][2] |
|---|---|---|---|---|---|
| H | X | X | Not selected | $I_{SB1}$, $I_{SB2}$ | Hi-Z |
| L | H | H | Output disabled | $I_{DDR}$ | Hi-Z |
| L | L | H | Byte Read | $I_{DDR}$ | $D_{Out}$ |
| L | X | L | Byte Write | $I_{DDW}$ | $D_{in}$ |

[1] H = high, L = low, X = don't care

[2] Hi-Z = high impedance

## 2. ELECTRICAL SPECIFICATIONS

### Absolute Maximum Ratings

This device contains circuitry to protect the inputs against damage caused by high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage greater than maximum rated voltages to these high-impedance (Hi-Z) circuits.

The device also contains protection against external magnetic fields. Precautions should be taken to avoid application of any magnetic field more intense than the maximum field intensity specified in the maximum ratings.

**Table 2.1 Absolute Maximum Ratings[1]**

| Parameter | Symbol | Value | Unit |
|---|---|---|---|
| Supply voltage[2] | $V_{DD}$ | -0.5 to 4.0 | V |
| Voltage on an pin[2] | $V_{IN}$ | -0.5 to $V_{DD}$ + 0.5 | V |
| Output current per pin | $I_{OUT}$ | ±20 | mA |
| Package power dissipation | $P_D$ | 0.600 | W |
| Temperature under bias | $T_{BIAS}$ | -45 to 130 | °C |
| Storage Temperature | $T_{stg}$ | -55 to 150 | °C |
| Lead temperature during solder (3 minute max) | $T_{Lead}$ | 260 | °C |
| Maximum magnetic field during write | $H_{max\_write}$ | 2000 | A/m |
| Maximum magnetic field during read or standby | $H_{max\_read}$ | 8000 | A/m |

1 Permanent device damage may occur if absolute maximum ratings are exceeded. Functional operation should be restricted to recommended operating conditions. Exposure to excessive voltages or magnetic fields could affect device reliability.

2 All voltages are referenced to $V_{SS}$.

3 Power dissipation capability depends on package characteristics and use environment.

**Table 2.2 Operating Conditions**

| Parameter | Symbol | Value | Typical | Max | Unit |
|---|---|---|---|---|---|
| Power supply voltage | $V_{DD}$ | 3.0 [i] | 3.3 | 3.6 | V |
| Write inhibit voltage | $V_{WI}$ | 2.5 | 2.7 | 3.0 [i] | V |
| Input high voltage | $V_{IH}$ | 2.2 | - | $V_{DD}$ + 0.3 [ii] | V |
| Input low voltage | $V_{IL}$ | -0.5 [iii] | - | 0.8 | V |
| Temperature under bias[iv] | $T_A$ | -40 | | 125 | °C |

[i] There is a 2 ms startup time once $V_{DD}$ exceeds $V_{DD}$(min). See **Power Up and Power Down Sequencing** below.

[ii] $V_{IH}$(max) = $V_{DD}$ + 0.3 $V_{DC}$; $V_{IH}$(max) = $V_{DD}$ + 2.0 $V_{AC}$ (pulse width ≤ 10 ns) for I ≤ 20.0 mA.

[iii] $V_{IL}$(min) = -0.5 $V_{DC}$ ; $V_{IL}$(min) = -2.0 $V_{AC}$ (pulse width ≤ 10 ns) for I ≤ 20.0 mA.

[iv] Automotive temperature profile assumes 10% duty cycle at maximum temperature (2-years out of 20-year life)

### Power Up and Power Down Sequencing

MRAM is protected from write operations whenever $V_{DD}$ is less than $V_{WI}$. As soon as $V_{DD}$ exceeds $V_{DD}$(min), there is a startup time of 2 ms before read or write operations can start. This time allows memory power supplies to stabilize.

The $\overline{E}$ and $\overline{W}$ control signals should track $V_{DD}$ on power up to $V_{DD}$- 0.2 V or $V_{IH}$ (whichever is lower) and remain high for the startup time. In most systems, this means that these signals should be pulled up with a resistor so that signal remains high if the driving signal is Hi-Z during power up. Any logic that drives $\overline{E}$ and $\overline{W}$ should hold the signals high with a power-on reset signal for longer than the startup time.

During power loss or brownout where $V_{DD}$ goes below $V_{WI}$, writes are protected and a startup time must be observed when power returns above $V_{DD}$(min).

**Figure 2.1 Power Up and Power Down Diagram**

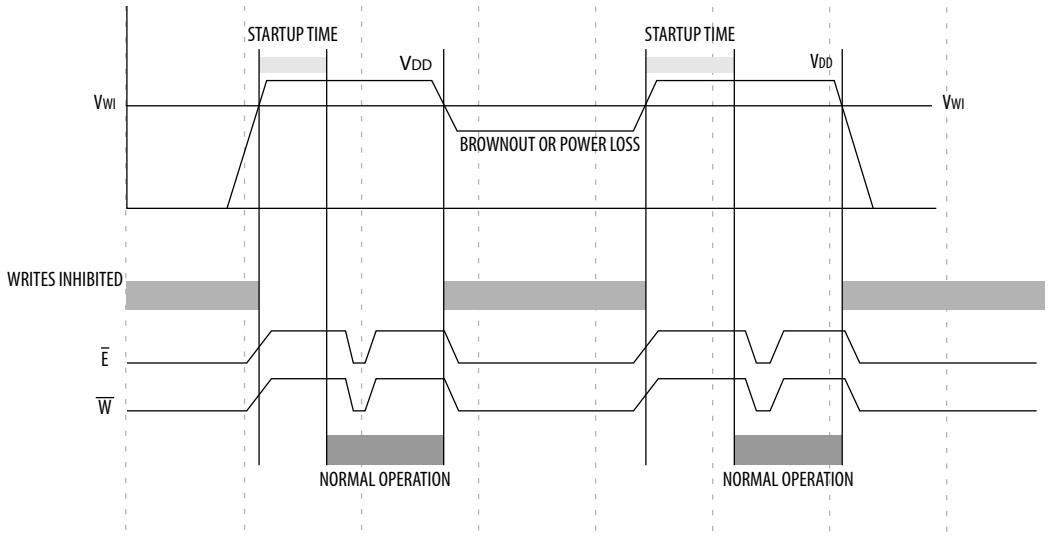


**Table 2.3 DC Characteristics**

| Parameter | Symbol | Min | Typical | Max | Unit |
|---|---|---|---|---|---|
| Input leakage current | $I_{lkg(I)}$ | - | - | ±1 | µA |
| Output leakage current | $I_{lkg(O)}$ | - | - | ±1 | µA |
| Output low voltage<br>($I_{OL}$ = +4 mA)<br>($I_{OL}$ = +100 µA) | $V_{OL}$ | - | - | 0.4<br>$V_{SS}$ + 0.2 | V |
| Output high voltage<br>($I_{OL}$ = -4 mA)<br>($I_{OL}$ = -100 µA) | $V_{OH}$ | 2.4<br>$V_{DD}$ - 0.2 | - | - | V |

**Table 2.4 Power Supply Characteristics**

| Parameter | Symbol | Typical | Max | Unit |
|---|---|---|---|---|
| AC active supply current - read modes[1]<br>($I_{OUT}$= 0 mA, $V_{DD}$= max) | $I_{DDR}$ | 30 | 66 | mA |
| AC active supply current - write modes[1]<br>($V_{DD}$= max) | $I_{DDW}$ | 50 | 135 | mA |
| AC standby current<br>($V_{DD}$= max, $\overline{E} = V_{IH}$)<br>*no other restrictions on other inputs* | $I_{SB1}$ | 13 | 20 | mA |
| CMOS standby current<br>($E \geq V_{DD}$ - 0.2 V and $V_{In} \leq V_{SS}$ + 0.2 V or ≥ $V_{DD}$ - 0.2 V)<br>($V_{DD}$ = max, f = 0 MHz) | $I_{SB2}$ | 8 | 10 | mA |

[1] All active current measurements are measured with one address transition per cycle and at minimum cycle time.

## 3. TIMING SPECIFICATIONS

**Table 3.1 Capacitance[1]**

| Parameter | Symbol | Typical | Max | Unit |
|---|---|---|---|---|
| Address input capacitance | $C_{In}$ | - | 6 | pF |
| Control input capacitance | $C_{In}$ | - | 6 | pF |
| Input/Output capacitance | $C_{I/O}$ | - | 8 | pF |

[1] f = 1.0 MHz, dV = 3.0 V, $T_A$ = 25 °C, periodically sampled rather than 100% tested.

**Table 3.2 AC Measurement Conditions**

| Parameter | Value | Unit |
|---|---|---|
| Logic input timing measurement reference level | 1.5 | V |
| Logic output timing measurement reference level | 1.5 | V |
| Logic input pulse levels | 0 or 3.0 | V |
| Input rise/fall time | 2 | ns |
| Output load for low and high impedance parameters | See Figure 3.1 | |
| Output load for all other timing parameters | See Figure 3.2 | |

**Figure 3.1 Output Load Test Low and High**

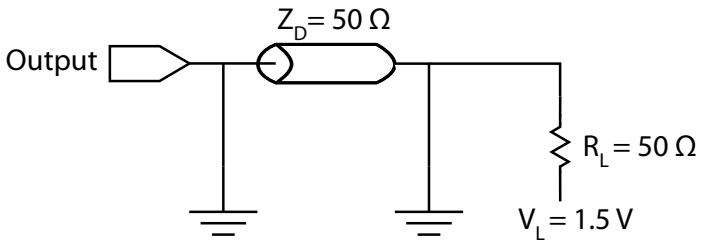
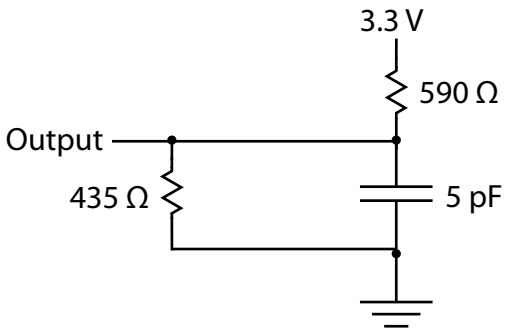



**Figure 3.2 Output Load Test All Others**



## Read Mode

**Table 3.3 Read Cycle Timing[1]**

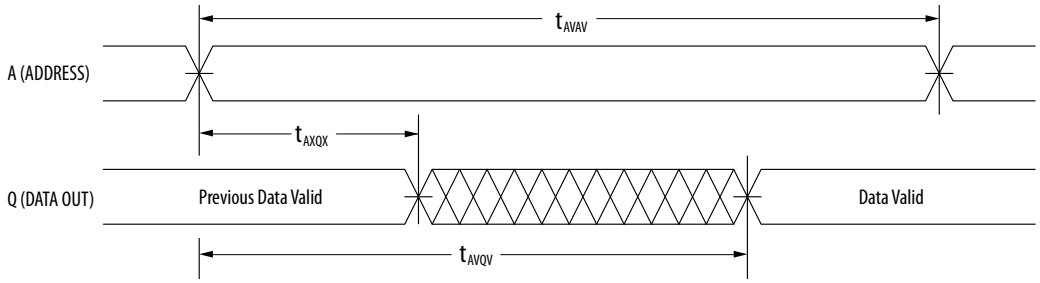
| Parameter | Symbol | Min | Max | Unit |
|---|---|---|---|---|
| Read cycle time | $t_{AVAV}$ | 35 | - | ns |
| Address access time | $t_{AVQV}$ | - | 35 | ns |
| Enable access time[2] | $t_{ELQV}$ | - | 35 | ns |
| Output enable access time | $t_{GLQV}$ | - | 15 | ns |
| Output hold from address change | $t_{AXQX}$ | 3 | - | ns |
| Enable low to output active[3] | $t_{ELQX}$ | 3 | - | ns |
| Output enable low to output active[3] | $t_{GLQX}$ | 0 | - | ns |
| Enable high to output Hi-Z[3] | $t_{EHQZ}$ | 0 | 15 | ns |
| Output enable high to output Hi-Z[3] | $t_{GHQZ}$ | 0 | 10 | ns |

1 $\overline{W}$ is high for read cycle. Power supplies must be properly grounded and decoupled, and bus contention conditions must be minimized or eliminated during read or write cycles.

2 Addresses valid before or at the same time $\overline{E}$ goes low.

3 This parameter is sampled and not 100% tested. Transition is measured ±200 mV from the steady-state voltage.

**Figure 3.3A Read Cycle 1**




Note: Device is continuously selected ($\overline{E} \leq V_{IL}$, $\overline{G} \leq V_{IL}$).

**Figure 3.3B Read Cycle 2**

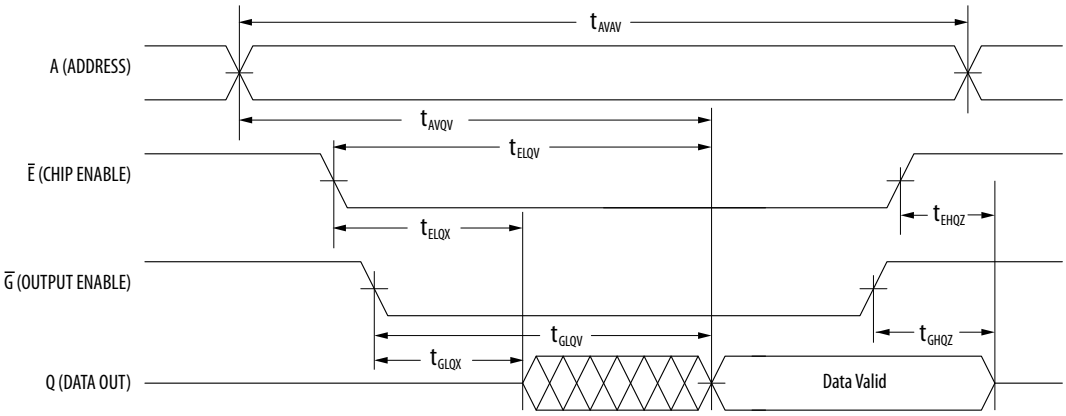


**Table 3.4 Write Cycle Timing 1 ($\overline{W}$ Controlled)[1]**

| Parameter | Symbol | Min | Max | Unit |
|---|---|---|---|---|
| Write cycle time[2] | $t_{AVAV}$ | 35 | - | ns |
| Address set-up time | $t_{AVWL}$ | 0 | - | ns |
| Address valid to end of write ($\overline{G}$ high) | $t_{AVWH}$ | 18 | - | ns |
| Address valid to end of write ($\overline{G}$ low) | $t_{AVWH}$ | 20 | - | ns |
| Write pulse width ($\overline{G}$ high) | $t_{WLWH}$ $t_{WLEH}$ | 15 | - | ns |
| Write pulse width ($\overline{G}$ low) | $t_{WLWH}$ $t_{WLEH}$ | 15 | - | ns |
| Data valid to end of write | $t_{DVWH}$ | 10 | - | ns |
| Data hold time | $t_{WHDX}$ | 0 | - | ns |
| Write low to data Hi-Z[3] | $t_{WLQZ}$ | 0 | 12 | ns |
| Write high to output active[3] | $t_{WHQX}$ | 3 | - | ns |
| Write recovery time | $t_{WHAX}$ | 12 | - | ns |

[1] All write occurs during the overlap of $\overline{E}$ low and $\overline{W}$ low. Power supplies must be properly grounded and decoupled and bus contention conditions must be minimized or eliminated during read and write cycles. If $\overline{G}$ goes low at the same time or after $\overline{W}$ goes low, the output will remain in a high impedance state. After $\overline{W}$ or $\overline{E}$ has been brought high, the signal must remain in steady-state high for a minimum of 2 ns. The minimum time between $\overline{E}$ being asserted low in one cycle to $\overline{E}$ being asserted low in a subsequent cycle is the same as the minimum cycle time allowed for the device.

[2] All write cycle timings are referenced from the last valid address to the first transition address.

[3] This parameter is sampled and not 100% tested. Transition is measured ±200 mV from the steady-state voltage. At any given voltage or temperate, $t_{WLQZ}$(max) < $t_{WHQX}$(min)

**Figure 3.4 Write Cycle Timing 1 ($\overline{W}$ Controlled)**

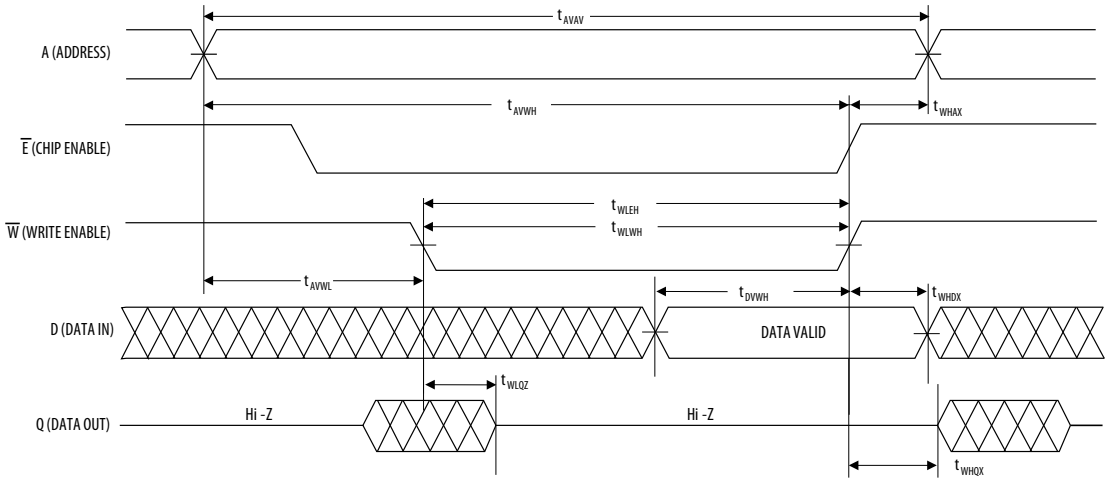


**Table 3.5 Write Cycle Timing 2 ($\overline{E}$ Controlled)[1]**

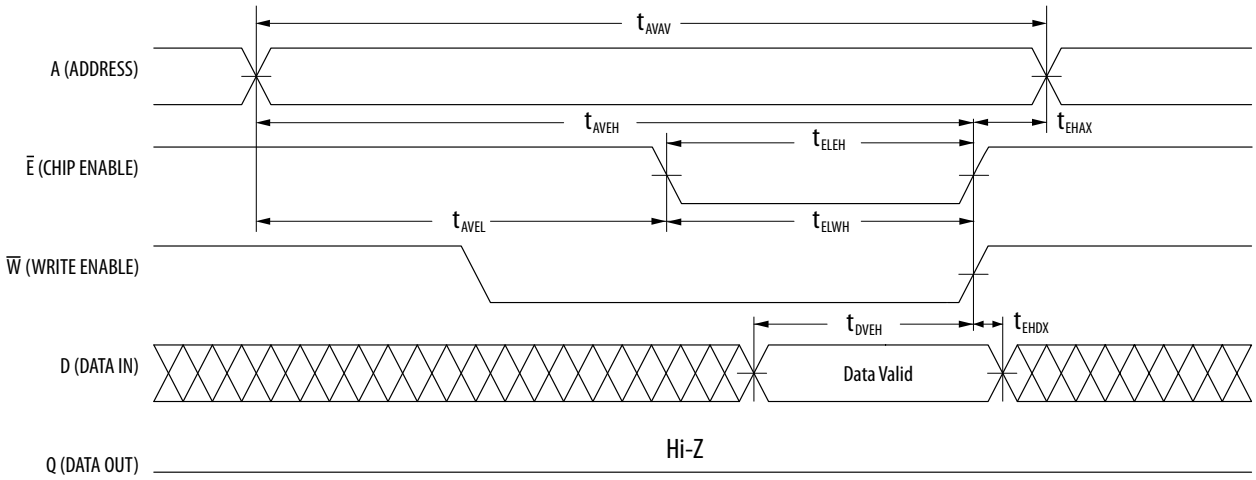
| Parameter | Symbol | Min | Max | Unit |
|---|---|---|---|---|
| Write cycle time[2] | $t_{AVAV}$ | 35 | - | ns |
| Address set-up time | $t_{AVEL}$ | 0 | - | ns |
| Address valid to end of write ($\overline{G}$ high) | $t_{AVEH}$ | 18 | - | ns |
| Address valid to end of write ($\overline{G}$ low) | $t_{AVEH}$ | 20 | - | ns |
| Enable to end of write ($\overline{G}$ high) | $t_{ELEH}$<br>$t_{ELWH}$ | 15 | - | ns |
| Enable to end of write ($\overline{G}$ low)[3] | $t_{ELEH}$<br>$t_{ELWH}$ | 15 | - | ns |
| Data valid to end of write | $t_{DVEH}$ | 10 | - | ns |
| Data hold time | $t_{EHDX}$ | 0 | - | ns |
| Write recovery time | $t_{EHAX}$ | 12 | - | ns |

[1] All write occurs during the overlap of $\overline{E}$ low and $\overline{W}$ low. Power supplies must be properly grounded and decoupled and bus contention conditions must be minimized or eliminated during read and write cycles. If $\overline{G}$ goes low at the same time or after W goes low, the output will remain in a high impedance state. After $\overline{W}$ or $\overline{E}$ has been brought high, the signal must remain in steady-state high for a minimum of 2 ns. The minimum time between $\overline{E}$ being asserted low in one cycle to $\overline{E}$ being asserted low in a subsequent cycle is the same as the minimum cycle time allowed for the device.

[2] All write cycle timings are referenced from the last valid address to the first transition address.

[3] If $\overline{E}$ goes low at the same time or after $\overline{W}$ goes low, the output will remain in a high-impedance state. If $\overline{E}$ goes high at the same time or before $\overline{W}$ goes high, the output will remain in a high-impedance state.

**Figure 3.5 Write Cycle Timing 2 ($\overline{E}$Controlled)**



## 4. ORDERING INFORMATION

**Figure 4.1 Part Numbering System**

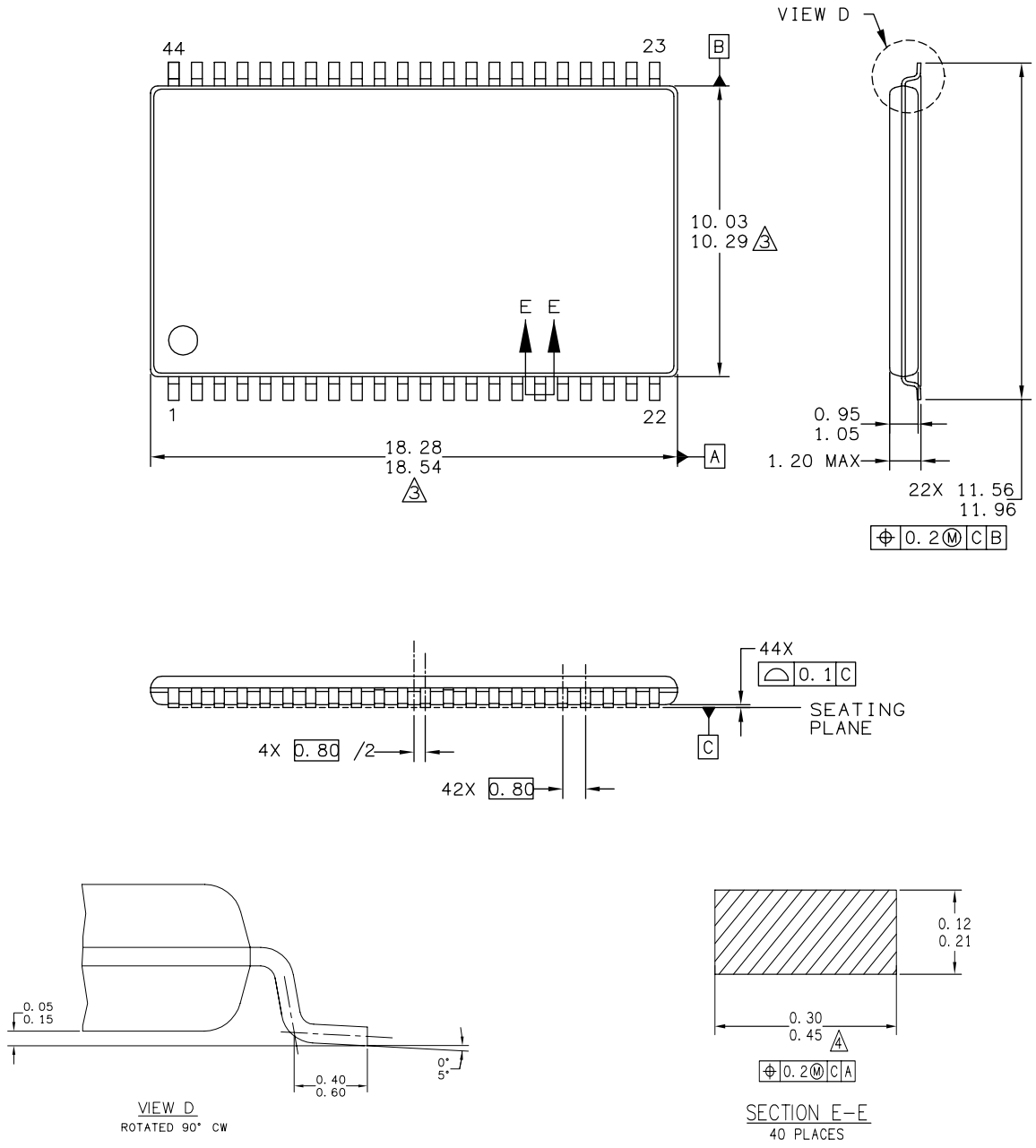
| MR | 2 | A | 08 | A | M | YS | 35 | R | | |
|---|---|---|---|---|---|---|---|---|---|---|
| | | | | | | | | | Carrier | (Blank = Tray, R = Tape & Reel) |
| | | | | | | | | | Speed | (35 ns) |
| | | | | | | | | | Package | (YS = TSOPII) |
| | | | | | | | | | Temperature Range | (M= -40 to +125 °C) |
| | | | | | | | | | Revision | |
| | | | | | | | | | Data Width | (08 = 8-Bit) |
| | | | | | | | | | Type | (A = Asynchronous) |
| | | | | | | | | | Density | (2 =4Mb) |
| | | | | | | | | | Magnetoresistive RAM | (MR) |

**Table 4.1 Available Parts**

| Part Number | Description | Temperature |
|---|---|---|
| MR2A08AMYS35 | 3.3 V 512Kx8 MRAM 44-TSOP | Automotive |
| MR2A08AMYS35R | 3.3 V 512Kx8 MRAM 44-TSOP T&R | Automotive |

## 5. MECHANICAL DRAWING

**Figure 5.1 TSOP-II**




**Print Version Not To Scale**

1. Dimensions and tolerances per ASME Y14.5M - 1994.
2. Dimensions in Millimeters.
3. Dimensions do not include mold protrusion.
4. Dimension does not include DAM bar protrusions.
   DAM Bar protrusion shall not cause the lead width to exceed 0.58.

## 6. REVISION HISTORY

| Revision | Date | Description of Change |
|---|---|---|
| 0 | Feb 28, 2011 | Initial Release from original MR2A08A datasheet. |

Unless otherwise noted, this is a Production Product - This product conforms to specifications per the terms of the Everspin standard warranty. The product has completed Everspin internal qualification testing and has reached production status.

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